

Preliminary

SIDC73D170E6

Fast switching diode chip in EMCON-Technology

FEATURES:

- 1700V EMCON technology 200 µm chip
- soft , fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

 EUPEC power modules and discrete devices



Applications:

• SMPS, resonant applications, drives

| Chip Type | V _R | I _F | Die Size | Package | Ordering Code |
|--------------|----------------|----------------|-----------------------------|--------------|-----------------------|
| SIDC73D170E6 | 1700V | 100A | 8.53 x 8.53 mm ² | sawn on foil | Q67050-A4173- A001 |

MECHANICAL PARAMETER:

| Raster size | 8.53 x 8.53 | | | | |
|---------------------------------|--|-----------------|--|--|--|
| Area total / active | 72.76 / 54.17 | mm ² | | | |
| Anode pad size | 6.51 x 6.51 | | | | |
| Thickness | 200 | μm | | | |
| Wafer size | 150 | mm | | | |
| Flat position | 180 | deg | | | |
| Max. possible chips per wafer | 190 pcs | | | | |
| Passivation frontside | Photoimide | | | | |
| Anode metalization | 3200 nm Al Si Cu | | | | |
| Cathode metalization | 1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding | | | | |
| Die bond | electrically conductive glue or solder | | | | |
| Wire bond | | | | | |
| Reject Ink Dot Size | Ø 0.65mm | | | | |
| Recommended Storage Environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C | | | | |



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Maximum Ratings

| Parameter | Symbol | Condition | Value | Unit |
|--|---------------------|-----------------------------------|---------|------|
| Repetitive peak reverse voltage | V _{RRM} | | 1700 | V |
| Continuous forward current limited by | I _F | | 100 | |
| T _{jmax} | 'F | | 100 | |
| Single pulse forward current | I _{FSM} | t _P = 10 ms sinusoidal | tbd | А |
| (depending on wire bond configuration) | ·F3M | | | |
| Maximum repetitive forward current | 1 | | 200 | |
| limited by T _{jmax} | I _{FRM} | | 200 | |
| Operating junction and storage temperature | T_{j} , T_{stg} | | -55+150 | °C |

Static Electrical Characteristics (tested on chip), T_j =25 °C, unless otherwise specified

| Parameter | Symbol | Cond | Value | | | Unit | |
|------------------------------------|-----------------|-----------------------|-------------------------------------|------|------|------|------|
| Falameter | Symbol | Conditions | | min. | Тур. | max. | Onic |
| Reverse leakage current | I _R | V _R =1700V | <i>T_j</i> =25 ° <i>C</i> | | | 27 | μA |
| Cathode-Anode breakdown Voltage | V _{Br} | I _R =4mA | <i>T_j</i> =25°C | 1700 | | | V |
| Forward voltage drop | V _F | I _F =100A | <i>T_j</i> =25°C | | 2.15 | | V |

Dynamic Electrical Characteristics, at T_j = 25 °C, unless otherwise specified, tested at component

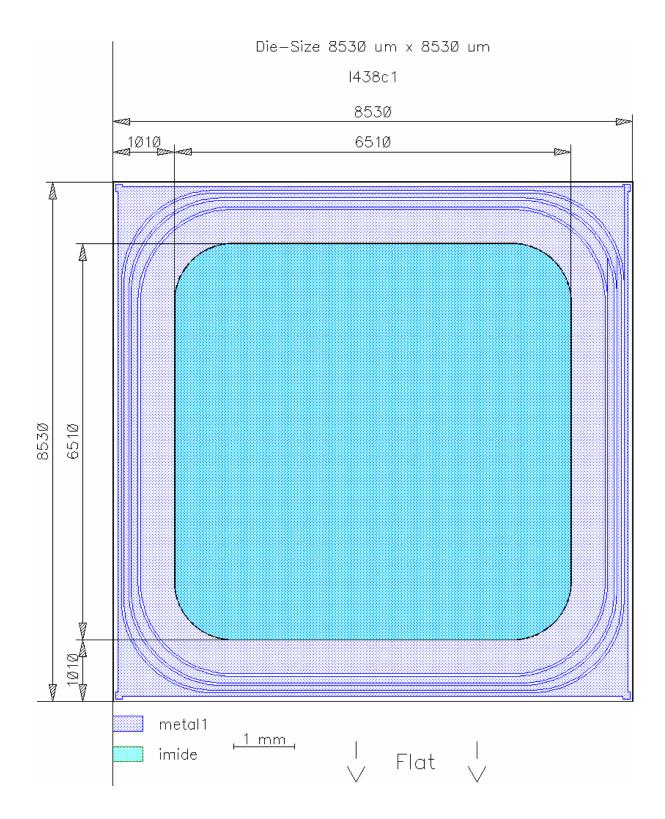
| Parameter | Symbol | Conditions | | Value | | | Unit | |
|------------------------------|-----------------------|---|-----------------------------|-------|------|------|-------|--|
| Falameter | Symbol | | | min. | Тур. | max. | | |
| Reverse recovery time | t _{rr1} | I _F =100A | $T_j = 25 \ ^{\circ}C$ | | tbd | | | |
| | t _{rr2} | <i>di/dt</i> =1700A/ m s V _R =900V | $T_j = 150 \ ^\circ C$ | | | | ns | |
| Peak recovery current | I _{RRM1} | $I_F=100A$ | $T_j = 25 \ ^{\circ}C$ | | 110 | | ^ | |
| | I _{RRM2} | <i>di/dt=1700A/ms</i> <i>V_R=900V</i> | $T_j = 150 \ ^\circ C$ | | 130 | | A | |
| Reverse recovery charge | Q _{rr1} | $I_{F}=100A$ | <i>T_j</i> =25 °C | | 35 | | | |
| | Q _{rr2} | di/dt=1700A/ms V _R =900V | T _j =150°C | | 60 | | μC | |
| Peak rate of fall of reverse | di _{rr1} /dt | I _F =100A | $T_j = 25 ^{\circ}C$ | | tbd | | A / - | |
| recovery current | di _{rr2} /dt | <i>di/dt</i> =1700A/ m s V _R =900V | <i>T_j</i> =150°C | | | | ·A/μs | |
| Softness | S1 | I _F =100A | <i>T_j</i> =25 °C | | tbd | | 1 | |
| | S2 | <i>di/dt</i> =1700A/ m s V _R =900V | <i>T_j</i> =150°C | | | | | |



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CHIP DRAWING:





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FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the | INFINEON TECHNOLOGIES / | tbd |
|------------------------------------|-------------------------|-----|
| device data sheet | EUPEC | lbu |

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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